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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/506,716-Conf. #4876
				Filing Date	September 7, 2004
				First Named Inventor	Peter Hoghoj
				Art Unit	2882
				Examiner Name	J. Corbett
Sheet	1	of	1	Attorney Docket Number	XENOCs 3.3-001

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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FOREIGN PATENT DOCUMENTS						
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/JMC/	CA	KLEINEBERG et al., "Bufferlayer and Caplayer Engineering of Mo/Si EUVL Multilayer Mirrors", Soft X-Ray and EUV Imaging Systems II, Daniel A. Tichenor, James A. Folta, Editors, Proceedings of SPIE, Vol. 4506 (2001), pp. 113-120.			
/JMC/	CB	NIGGEMEIER et al., "X-ray Reflectometer for the Diagnostics of Thin Films During Growth", Journal of Applied Crystallography (1997), 30, 905-908.			

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Examiner Signature	/John Corbett/	Date Considered	1 June 2007
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Patent 11000